般積層セラミックコンデンサ

(高誘電率系·Class 2)

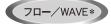
STANDARD MULTILAYER CERAMIC CAPACITORS (CLASS2:HIGH DIELECTRIC CONSTANT TYPE)

	code	Temp.characteristics	operating Temp. range
		В	-25~+85°C
	B/BJ	X7R	-55~+125°C
OPERATING TEMP.		X5R	-55~+85°C
	F	F	-25~+85°C
		Y5V	-30~+85°C











- *042TYPE, 063TYPE, 105TYPEは除く
- *Except for 042TYPE, 063TYPE, 105TYPE

特長 FEATURES

- ・実装密度の向上が図れます
- ・モノリシックの構造のため、信頼性が高い
- ・同一形状、静電容量範囲が広い

- · Improve Higher Mounting Densities.
- · Multilayer block structure provides higher reliability
- · A wide range of capacitance values available in standard case sizes.

用途 APPLICATIONS

- ·一般電子機器用
- ・通信機器用(携帯電話、PHS、コードレス電話 etc.)

- · General electronic equipment
- · Communication equipment (cellular phone, PHS, other wireless applications, etc.)

形名表記法 **ORDERING CODE**



U 50 シリーズ名 積層コンデンサ М

メッキ品

形状寸法 (EIA)L×W(mm) 042(01005) 0.4×0.2 063(0201) 0.6×0.3 105(0402) 1.0×0.5

1.6×0.8

107(0603)

△=スペース

温度特性 △B,BJ △F ±30 % 6 公称静電容量 [pF] 例 1000 102 223 22000

容量許容差〔%〕 ± 10 ±20 +80 -20 М Z

8 製品厚み (mm) 0.2 Р 0.3 V 0.5 Z 0.8

9 個別仕様 標準

O 包装 ーピング (2mmピッチ・178φ) テーピング (4mmピッチ・178φ)



3 端子電極

Rated	voltage(VDC)
Α	4
J	6.3
L	10
Е	16
Т	25
G	35
U	50

Series name M Multilayer ceramic capacitors

End termination

Dimensions (case size) (L×W) [mm] 042(01005) 0.4×0.2 063(0201) 0.6×0.3 105(0402) 1.0×0.5 107(0603)

6 Temperature characteristics code -55~+125°C $\triangle B$ ±15% -55~+85°C BJ ±15%

-30~+85°C +22 -82%

△=Blank space

 $\triangle F$ Y5V

Nominal Capacitance (pF) example 1000 102 223 22000

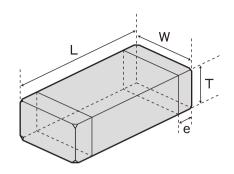
Capacitance Tolerance (%) ± 10 М ±20

8 Thickness (mm) 0.2 Р 0.3 ٧ 0.5 0.8 Special code Standard products

10 Packaging Tape&Reel (2mm pitch • 178 φ) Tape&Reel (4mm pitch • 178 φ)

△=Blank space

外形寸法 EXTERNAL DIMENSIONS



_ (=)			_		
Type (EIA)	L	W			е
☐MK042	0.4 ± 0.02	0.2 ± 0.02	0.2±0.02	С	0.1 ± 0.03
(01005)	(0.016±0.001)	(0.008 ± 0.001)	(0.008±0.001)	C	(0.004 ± 0.001)
☐MK063	0.6±0.03	0.3 ± 0.03	0.3±0.03	Р	0.15 ± 0.05
(0201)	(0.024±0.001)	(0.012 ± 0.001)	(0.012±0.001)	Р	(0.006 ± 0.002)
☐MK105	1.0±0.05	0.5 ± 0.05	0.5±0.05	V	0.25±0.10
(0402)	(0.039 ± 0.002)	(0.020 ± 0.002)	(0.020±0.002)	V	(0.010 ± 0.002)
☐MK107	1.6±0.10	0.8±0.10	0.8±0.10	7	0.35±0.25
(0603)	(0.063±0.004)	(0.031 ± 0.004)	(0.031±0.004)		(0.014±0.010)

Unit: mm (inch)

概略バリエーション AVAILABLE CAPACITANCE RANGE

■汎用積層セラミックコンデンサ (General Multilayer Ceramic capacitors)

	Type	04	42				0	63											10	05								10)7	
Te	emp.char.	B/>	(5R		B/X	(5R		Χŧ	5R	F/Y	′5V		B/X7F	1			B/>	(5R		Χŧ	5R			F/Y5V	'		B/X	(7R	F/	Y5V
	WV																													
Cap		10V	6.3V	25V	16V	10V	6.3V	6.3V	4V	6.3V	4V	50V	25V	16V	35V	25V	16V	10V	6.3V	6.3V	4V	50V	25V	16V	10V	6.3V	50V	25V	50V	25\
[pF]	[pF 3digits]																													
100 150 220 330 470 680 1000 1500 220 3300 4700 6800 10000 15000 33000 47000 6800 100000 33000 47000 33000 47000 330000 47000	101 151 221 331 471 681 102 152 222 332 472 682 103 153 223 333 473 683 104 224 334 474 105	С	С	P	P	P	P	P	P	P	P	V	V	V	V	V	V	V	V			V	V	V	V	V	Z	Z	Z	Z
2200000 3300000 4700000	225 335 475																			V	V					·				

注:グラフの記号は製品厚み記号です。Note: Letter codes in shaded areas are thickness codes.

温度特性コード			温度特性 Temperature chara			静電容量許容差[%]	tan δ (%)
Temp. char.Code	準排	U規格	温度範囲〔℃〕	基準温度〔℃〕	容量変化率 [%]	Capacitance tolerance	Dissipation factor
	Applicab	le standard	Temperature range	Ref. Temp.	Capacitance change		
BJ	JIS	В	-25~85	20	±10	±20 (M)	0.50/**
	EIA	X7R*	-55~125	25	±15	±10 (K)	2.5%max.**
_	JIS	F	-25~85	20	+30/-80	+80	7.0%max.**
F	EIA	Y5V	-30~85	25	+22/-82	-20 ^(Z)	7.070111dx.

- *: X5Rのみ対応するアイテムがあります。詳細はアイテム一覧を参照ください。
- **: 代表定期な値を記載しています。詳細はアイテム一覧を参照ください。
- * : Some of parts are only applicable to X5R. Please refer to PART NUMBERS table.
- **: The figure indicate typical value. Please refer to PART NUMBERS table.













042TYPE(01005 case size) -

定格 電圧	形名	EH (Environ	mental	公 称 静電容量	温度特性	tan δ Dissipation	実装条件 Soldering method	静電容量 許容差	厚み
Rated Voltage (DC)	Ordering code	Hazan		Capacitance	Temp.Char	factor [%]Max.	R:リフロー Reflow soldering W: フロー Wave soldering	Capacitance	Thickness hmmi(inch)
(DC)		Substa	inces)	(pF)		[%]Max.	vv: /u- vvave soldering	tolerance	nmmi (incn)
	LMK042 BJ101□C	Rol	HS	100					
	LMK042 BJ151□C	Rol	HS	150				±10%	
	LMK042 BJ221□C	Rol	HS	220					
10V	LMK042 BJ331□C	Rol	HS	330		5			
	LMK042 BJ471□C	Rol	HS	470					
	LMK042 BJ681□C	Rol	HS	680					0.2±0.02
	LMK042 BJ102□C	Rol	HS	1000	B/X5R		R	±20%	(0.008±0.001)
	JMK042 BJ152□C*	Rol	HS	1500					(0.000±0.001)
	JMK042 BJ222□C*	Rol	HS	2200					
6.3V	JMK042 BJ332□C*	Rol	HS	3300		10			
0.57	JMK042 BJ472□C*	Rol	HS	4700		10			
	JMK042 BJ682□C*	Rol	HS	6800					
	JMK042 BJ103□C*	Rol	HS	10000					

形名の□には静電容量許容差記号が入ります。

063TYPE(0201 case size) -

000111 L(0201 case size)										
定格電圧	形名	(Fn.	EHS vironmental	公 称 静電容量	温度特性	tan δ Dissipation	実装条件 Soldering method	静電容量 許容差	厚み	
		,	azardous			factor	R:U7D— Reflow soldering		Thistmass	
Rated Voltage	Ordering code			Capacitance	Temp.Char			Capacitance	Thickness	
(DC)		Su	bstances)	(pF)		(%)Max.	W: フロー Wave soldering	tolerance	hmmi (inch)	
	TMK063 BJ101□P		RoHS	100						
	TMK063 BJ151□P		RoHS	150						
	TMK063 BJ221□P		RoHS	220						
25V	TMK063 BJ331□P		RoHS	330		3.5				
	TMK063 BJ471□P		RoHS	470						
	TMK063 BJ681□P		RoHS	680						
	TMK063 BJ102□P		RoHS	1000					0.3±0.03 (0.012±0.001)	
	EMK063 BJ152□P		RoHS	1500	B/X5R			±10%		
16V	EMK063 BJ222□P		RoHS	2200				±20%		
	EMK063 BJ332□P		RoHS	3300		5	R			
	LMK063 BJ472□P		RoHS	4700		3	n n			
10V	LMK063 BJ682□P		RoHS	6800					(0.012±0.001)	
100	LMK063 BJ103□P		RoHS	10000						
	LMK063 BJ223 P*		RoHS	22000		7.5				
	JMK063 BJ473□P*		RoHS	47000		7.5				
6.3V	JMK063 BJ104□P*		RoHS	100000						
	JMK063 BJ224MP*		RoHS	220000						
	AMK063 BJ224MP*		RoHS	220000	X5R	10		±20%		
4V	AMK063 BJ334MP*		RoHS	330000				120 /0		
	AMK063 BJ474MP*		RoHS	470000						
6.3V	JMK063 F223ZP		RoHS	22000				1.000/		
0.30	JMK063 F473ZP		RoHS	47000	F/Y5V	12.5		+80%		
4V	AMK063 F104ZP		RoHS	100000				-20%		

形名の□には静電容量許容差記号が入ります。

^{*} 高温負荷試験の試験電圧は定格電圧の1.5倍

 $[\]hfill\square \mbox{Please}$ specify the capacitance tolerance code.

^{*} Test voltage of Loading at high temperature test is 1.5 time of the rated voltage.

^{*}高温負荷試験の試験電圧は定格電圧の1.5倍

[☐]Please specify the capacitance tolerance code.

^{*} Test voltage of Loading at high temperature test is 1.5 time of the rated voltage.

105TYPE(0402 case size) -

定格電圧 Rated Voltage (DC)	形 名 Ordering code	EHS (Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temp.Char	tan δ Dissipation factor (%) Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚 み Thickness (mm)(inch)
	UMK105 BJ221□V	RoHS	220					
	UMK105 BJ331□V	RoHS	330					
	UMK105 BJ471□V	RoHS	470					1
50V	UMK105 BJ681□V	RoHS	680	B/X7R				
30 V	UMK105 BJ102□V	RoHS	1000		2.5			
	UMK105 BJ152□V	RoHS	1500		2.5			
	UMK105 BJ222□V	RoHS	2200					
	UMK105 BJ332□V	RoHS	3300					
35V	GMK105 BJ104□V*	RoHS	100000	B/X5R	5			
	TMK105 BJ472□V	RoHS	4700		2.5			
25V	TMK105 BJ682□V	RoHS	6800	B/X7R	2.5			
25V	TMK105 BJ103□V	RoHS	10000		3.5			
	TMK105 BJ104□V*	RoHS	100000	B/X5R	5			
	EMK105 BJ153□V	RoHS	15000				±10% ±20%	
	EMK105 BJ223□V	RoHS	22000		3.5			
	EMK105 BJ333□V	RoHS	33000	B/X7R	3.5			
16V	EMK105 BJ473□V	RoHS	47000					
	EMK105 BJ104□V*	RoHS	100000%			R		
	EMK105 BJ104 V*	RoHS	100000			n n		0.5±0.05
	EMK105 BJ224 V*	RoHS	220000		5			0.5±0.05
	LMK105 BJ104□V	RoHS	100000					
	LMK105 BJ224 V*	RoHS	220000					
10V	LMK105 BJ474 V*	RoHS	470000		10			
	LMK105 BJ105□V*	RoHS	1000000	B/X5R	10			
	JMK105 BJ224□V*	RoHS	220000		5			
	JMK105 BJ474□V*	RoHS	470000					
6.3V	JMK105 BJ105□V*	RoHS	1000000					
	JMK105 BJ225MV*	RoHS	220000		10			
4V	AMK105 BJ335MV*	RoHS	330000	X5R			±20%	
4 V	AMK105 BJ475MV*	RoHS	470000					
50V	UMK105 F103ZV	RoHS	10000		5			
25V	TMK105 F223ZV	RoHS	22000					
16V	EMK105 F473ZV	RoHS	47000		7		+80%	
100	EMK105 F104ZV	RoHS	100000	F/Y5V	9		+80% −20%	
10V	LMK105 F224ZV	RoHS	220000		11		-20/0	
6.3V	JMK105 F474ZV	RoHS	470000		16			
0.57	JMK105 F105ZV*	RoHS	1000000		20			

形名の□には静電容量許容差記号が入ります。 * 高温負荷試験の試験電圧は定格電圧の1.5倍 ※品名末尾にRが付きます。

107TYPE(0603 case size) -

定格 電圧 Rated Voltage (DC)	形 名 Ordering code	`	EHS Environmental Hazardous Substances)	公 称 静電容量 Capacitance 〔pF〕	温度特性 Temp.Char	tan δ Dissipation factor [%]Max.	実装条件 Soldering method R:リフロー Reflow soldering W: フロー Wave soldering	静電容量 許 容 差 Capacitance tolerance	厚 み Thickness (mm)(inch)
	UMK107 B102□Z		RoHS	1000					
	UMK107 B152 Z		RoHS	1500					
	UMK107 B222□Z		RoHS	2200				±10%	
50V	UMK107 B332□Z		RoHS	3300)				
	UMK107 B472□Z		RoHS	4700	B/X7R	2.5		±20%	
	UMK107 B682□Z		RoHS	6800			W, R	120%	0.8±0.10
	UMK107 B103□Z		RoHS	10000			۷۷, ۲		(0.031±0.004)
25V	TMK107 B153□Z		RoHS	15000					(0.031±0.004)
234	TMK107 B223□Z		RoHS	22000					
50V	UMK107 F103ZZ		RoHS	10000					
307	UMK107 F223ZZ		RoHS	22000	E 0/5)/	5		+80%	
25V	TMK107 F473ZZ		RoHS	47000	F/Y5V	ا		-20%	
257	TMK107 F104ZZ		RoHS	100000					

形名の□には静電容量許容差記号が入ります。

[□] Please specify the capacitance tolerance code.

* Test voltage of Loading at high temperature test is 1.5 time of the rated voltage. *Internal Code shall be R.

[☐]Please specify the capacitance tolerance code.

梱包 PACKAGING

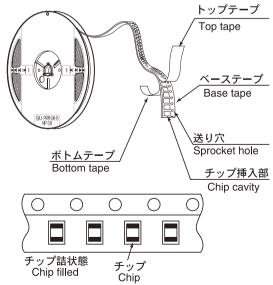
①最小受注単位数 Minimum Quantity

■テーピング梱包 Taped packaging

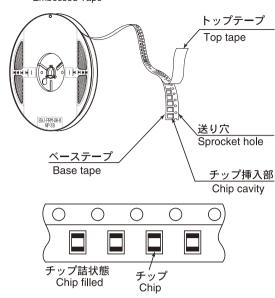
■ナーピング個型	raped packaging				
形式(EIA) Type	製品厚み Thickness			数量 d quantity s]	
турс	mm (inch)	code	紙テープ paper	エンボステープ Embossed tape	
☐MK042 (01005)	0.2 (0.008)	С	15000	_	
☐MK063(0201)	0.3 (0.012)	Р	15000	_	
□2K096(0302)	0.3 (0.012)	Р	10000		
□2K09b(0302)	0.45 (0.018)	K	10000	_	
☐MK105(0402)	0.5 (0.020)	V, W	10000		
□VK105 (0402)	0.5 (0.020)	W	10000	_	
	0.45 (0.018)	K	4000	_	
□MK107(0603)	0.5 (0.020)	V	_	4000	
□WK107(0306)	0.0(0.004)	Α	4000		
	0.8(0.031)	Z	4000	_	
□2K110(0504)	0.8(0.031)	Α	4000	_	
□2K110(0504)	0.6 (0.024)	В	4000	_	
	0.45 (0.018)	K	4000	_	
☐MK212(0805) ☐WK212(0508)	0.85 (0.033)	D	4000	_	
VVK212(0306)	1.25 (0.049)	G	_	3000	
□4K212(0805)	0.85 (0.033)	D	4000	_	
□2K212(0805)	0.85 (0.033)	D	4000	_	
	0.85 (0.033)	D	4000	_	
□MK316(1206)	1.15 (0.045)	F		2000	
□WK316(0612)	1.25 (0.049)	G	1 —	3000	
	1.6 (0.063)	L	_	2000	
	0.85 (0.033)	D			
	1.15 (0.045)	F		0000	
□ W(005(4040)	1.5 (0.059)	Н	_	2000	
□MK325(1210)	1.9 (0.075)	N			
	2.0max(0.079)	Υ	_	2000	
	2.5 (0.098)	М	_	500,1000	
	1.9 (0.075)	Υ	_	1000	
□MK432(1812)	2.5 (0.098)	М		500	
	3.2 (0.125)	U		500	

②テービング材質 Taping material 紙テープ Card board carrier tape

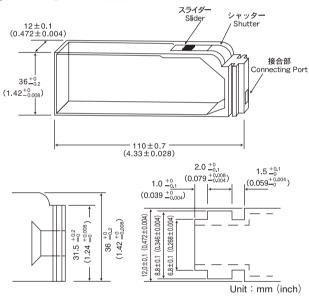
※プレスポケットタイプは、 ボトムテープ無し。



エンボステープ Embossed Tape

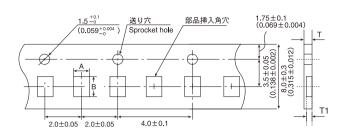


③バルクカセット Bulk Cassette

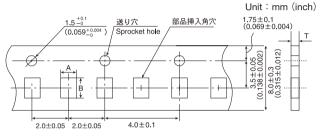


105, 107, 212形状で個別対応致しますのでお問い合せ下さい。 Please contact any of our offices for accepting your requirement according to dimensions 0402, 0603, 0805.(inch)

③テーピング寸法 Taping dimensions 紙テープ Paper Tape(8mm幅)(0.315inches wide)

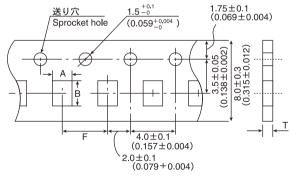


Time	チッフ	[°] 挿入部	挿入ピッチ	テープ厚み		
Type (EIA)	Chip (Cavity	Insertion Pitch	Tape Thickness		
(EIA)	Α	В	F	Т	T1	
□MK042(01005)	0.25	0.45	2.0±0.05	0.36max	0.27max.	
IMIKU42(U1005)	(0.010)	(0.018)	(0.079±0.002)	(0.014)	(0.011)	
	0.37	0.67	2.0±0.05	0.45max	0.42max.	
□MK063(0201)	(0.016)	(0.027)	(0.079±0.002)	(0.018)	(0.017)	



T	チッフ	[°] 挿入部	挿入ピッチ	テープ厚み
Type (EIA)	Chip (Cavity	Insertion Pitch	Tape Thickness
(EIA)	Α	В	F	Т
	0.72	1.02	2.0±0.05	0.45max.(0.018max)
□2K096(0302)	(0.028)	(0.040)	(0.079±0.002)	0.6max.(0.024max)
☐MK105(0402)	0.65	1.15	2.0±0.05	0.8max.
□VK105(0402)	(0.026)	(0.045)	(0.079±0.002)	(0.031max.)

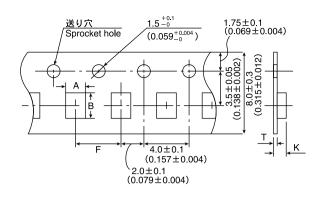
Unit: mm (inch)



Time	チップ挿入部		挿入ピッチ	テープ厚み
Type (EIA)	Chip Cavity		Insertion Pitch	Tape Thickness
(EIA)	Α	В	F	Т
☐MK107(0603)	1.0	1.8	4.0±0.1	1.1max.
□WK107(0306)	(0.039)	(0.071)	(0.157±0.004)	(0.043max.)
	1.15	1.55	4.0±0.1	1.0max.
□2K110 (0504)	(0.045)	(0.061)	(0.157±0.004)	(0.039max.)
☐MK212(0805)				
□WK212(0508)	1.65	2.4		
□4K212(0805)	(0.065)	(0.094)	4.0±0.1	1.1max.
□2K212(0805)			(0.157±0.004)	(0.043max.)
☐MK316(1206)	2.0	3.6]	
□WK316(0612)	(0.079)	(0.142)		

Unit: mm (inch)

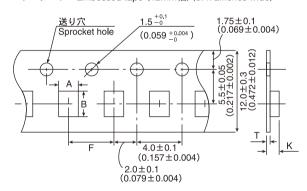
エンボステープ Embossed tape (8mm幅) (0.315inches wide)



Tuno	チップ	["] 挿入部	挿入ピッチ	テープ厚み	
Type	Chip	cavity Insertion Pitch		Tape Thickness	
(EIA)	А	В	F	K	Т
	1.0	1.8		1.3max.	0.25±0.1
□WK107 (0306)	(0.039)	(0.071)		(0.051max.)	(0.01±0.004)
□•#(0.40 (0.005)	1.65	2.4			
□MK212 (0805)	(0.065)	(0.094)	4.0±0.1		
	2.0	3.6	(0.157±0.004)	2.5max.	0.6max
□MK316 (1206)	(0.079)	(0.142)		(0.098max.)	(0.024max.)
□ N N (205 (4040)	2.8	3.6		3.4max.	
□MK325 (1210)	(0.110)	(0.142)		(0.134max.)	

Unit: mm (inch)

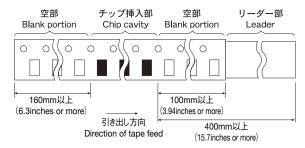
エンボステープ Embossed tape (12mm幅) (0.472inches wide)



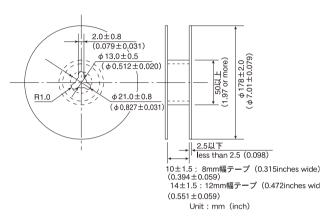
Туре	チップ挿入部		挿入ピッチ	テーフ	プ厚み
	Chip cavity		Insertion Pitch	Tape Th	ickness
(EIA)	А	В	F	K	T
□MK432 (1812)	3.7 (0.146)	4.9 (0.193)	8.0±0.1 (0.315±0.004)		0.6max. (0.024max.)

Unit: mm (inch)

④リーダー部/空部 Leader and Blank portion

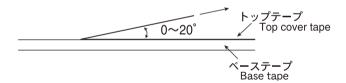


⑤リール寸法 Reel size



⑥トップテープ強度 Top Tape Strength

トップテープのはがし力は下図矢印方向にて $0.1\sim0.7$ Nとなります。 The top tape requires a peel-off force of $0.1\sim0.7$ N in the direction of the arrow as illustrated below.



Multilayer Ceramic Capacitor Chips

			Specific	ed Value		
It	em	Temperature Comp	pensating (Class 1)	High Permitiv	vity (Class 2)	Test Methods and Remarks
		Standard	High Frequency Type	Standard Note1	High Value	
I.Operating Range	Temperature	-55 to +125°C		BJ: -55 to +125°C F: -25 to +85°C	−25 to +85°C	High Capacitance Type BJ (X7R): -55~+125°C, BJ (X5R): -55~+85 E (Y5U): -30~+85°C, F (Y5V): -30~+85
2.Storage	Temperature	-55 to +125°C		BJ: -55 to +125°C F: -25 to +85°C	-25 to +85°C	High Capacitance Type BJ (X7R): -55~+125°C, BJ (X5R): -55~+85 E (Y5U): -30~+85°C, F (Y5V): -30~+85
3.Rated Volta	ge	50VDC,25VDC, 16VDC	16VDC 50VDC	50VDC,25VDC	50VDC,35VDC,25VDC 16VDC,10VDC,6.3VDC 4DVC, 2.5VDC	
4.Withstandin Between ter		No breakdown or damage	No abnormality	No breakdown or dama	ge	Applied voltage: Rated voltage ×3 (Class 1) Rated voltage ×2.5 (Class 2) Duration: 1 to 5 sec. Charge/discharge current: 50mA max. (Class 1,2)
5.Insulation R	esistance	10000 MΩ min.	I	500 M Ω μ F. or 10000 smaller.	$M\Omega$., whichever is the	Applied voltage: Rated voltage Duration: 60±5 sec. Charge/discharge current: 50mA max.
6.Capacitance	e (Tolerance)	0.5 to 5 pF: ±0.25 pF 1 to 10 pF: ±0.5 pF 5 to 10 pF: ±1 pF 11 pF or over: ±5% ±10% 105TYPERA, \$A, TA, UA only 0.5~2pF: ±0.1pF 2.2~20pF: ±5%	0.5 to 2 pF: ±0.1 pF 2.2 to 5.1 pF: ±5%	BJ: ±10%, ±20% F: +80% -20	BJ: ±10%、±20% F: -20%/+80%	Measuring frequency : Class1 : 1MHz±10% (C≤1000pF)
7.Q or Tangent (tan δ)	t of Loss Angle	Under 30 pF : Q≥400 + 20C 30 pF or over : Q≥1000 C= Nominal capacitance	Refer to detailed specification	BJ: 2.5% max. (50V, 25V) F: 5.0% max. (50V, 25V) Note 4	BJ: 2.5% max. F: 7% max. Note 4	Multilayer: Measuring frequency: $ \begin{array}{c} \text{Measuring frequency:} \\ \text{Class1: } 1\text{MHz}\pm10\% \text{ (C} \geq 1000\text{pF)} \\ \text{1 k Hz}\pm10\% \text{ (C} \geq 1000\text{pF)} \\ \text{Class2: } 1\text{ k Hz}\pm10\% \text{ (C} \leq 10\mu\text{ F)} \\ \text{120Hz}\pm10\text{Hz} \text{ (C} \geq 10\mu\text{ F)} \\ \text{Measuring voltage:} \\ \text{Note 4} \qquad \text{Class1: } 0.5 \sim 5\text{Vrms} \text{ (C} \leq 1000\text{pF)} \\ \text{1}\pm0.2\text{Vrms} \text{ (C} \leq 1000\text{pF)} \\ \text{Class2: } 1\pm0.2\text{Vrms} \text{ (C} \geq 10\mu\text{ F)} \\ \text{0.5}\pm0.1\text{Vrms} \text{ (C} \geq 10\mu\text{ F)} \\ \text{Bias application: None} \\ \text{High-Frequency-Multilayer:} \\ \text{Measuring frequency: } 1\text{GHz} \\ \text{Measuring equipment: } \text{HP4291A} \\ \text{Measuring ig: HP16192A} \\ \end{array} $
B.Temperature Characteristic of Capacitance	(Without voltage ap- plication)	CK: 0±250 CJ: 0±120 CH: 0±60 CG: 0±30 RH: -220±60 SK: -330±250 SJ: -330±120 SH: -330±60 TK: -470±250 TJ: -470±120 UK: -750±250 UJ: -750±120 SL: +350 to -1000 (ppm/C)	CH: 0±60 RH: -220±60 (ppm/°C)	BJ: ±10% (-25~85°C) F: +30% (-25~85°C) BJ (X7R): ±15% F (Y5V): +22% -82	BJ: ±10% (-25~+85°C) F: +30%/-80% (-25~+85°C) BJ (X7R, X5R): ±15% F (Y5V): +22%/-82%	According to JIS C 5102 clause 7.12. Temperature compensating: Measurement of capacitance at 20°C and 85°C shall b made to calculate temperature characteristic by the following equation. \(\frac{C_{85} - C_{20}}{C_{20} \times T} \times 10^6 \times (ppm/°C) \) High permittivity: Change of maximum capacitance deviation in step 1 to 5 \) Temperature at step 1: +20°C Temperature at step 2: minimum operating temperature Temperature at step 3: +20°C (Reference temperature) Temperature at step 4: maximum operating temperature Temperature at step 5: +20°C Reference temperature for X7R, X5R, Y5U and Y5V shall be +25°C
9.Resistance Substrate	to Flexure of	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5 pF, whichever is larger.	Appearance: No abnormality Capacitance change: Within±0.5 pF	Appearance: No abnormality Capacitance change: BJ: Within ±12.5% F: Within ±30%		Warp: 1mm Testing board: glass epoxy—resin substrate Thickness: 1.6mm (063 TYPE: 0.8mm) The measurement shall be made with board in the bent position 20 Board Warp Warp

Multilayer Ceramic Capacitor Chips

		Specifie	ed Value		
Item	Temperature Comp	pensating (Class 1)	High Permitti	vity (Class 2)	Test Methods and Remarks
	Standard	High Frequency Type	Standard Note1	High Value	
10.Body Strength	_	No mechanical damage.	_	_	High Frequency Multilayer: Applied force: 5N Duration: 10 sec. Press Chip L L W D.6L L W
11.Adhesion of Electrode				Applied force: 5N Duration: 30±5 sec. (01005, 0201, 0302 TYPE 2N) Hooked jig R=05 PChip Cross-section	
12.Solderability	At least 95% of termina	l electrode is covered by	new solder.		Solder temperature: 230±5°C Duration: 4±1 sec.
13.Resistance to soldering	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±2.5% Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	tan δ: Initial value Insulation resistance: In	Vithin ±7.5% (BJ) Vithin ±20% (F) Note 4	Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Solder temperature: 270±5°C Duration: 3±0.5 sec. Preheating conditions: 80 to 100°C, 2 to 5 min. or 5 to 10 min 150 to 200°C, 2 to 5 min. or 5 to 10 min Recovery: Recovery for the following period under the standard condition after the test. 6~24 hrs (Class 1) 24±2 hrs (Class 2)
14.Thermal shock	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±0.25pF Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	tan δ: Initial value Insulation resistance: In	Vithin ±7.5% (BJ) Vithin ±20% (F) Note 4	Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Conditions for 1 cycle: Step 1: Minimum operating temperature $^{+0}_{-3}$ °C 30±3 min Step 2: Room temperature 2 to 3 min Step 3: Maximum operating temperature $^{-0}_{13}$ °C 30±3 min Step 4: Room temperature 2 to 3 min Number of cycles: 5 times Recovery after the test: 6~24 hrs (Class 1) 24±2 hrs (Class 2)
15.Damp Heat (steady state)	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5pF, whichever is larger. Q: C≧30 pF : Q≧350 10 ≤ C < 30 pF: Q≧ 275 + 2.5C C<10 pF : Q≧200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±0.5pF, Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ tan δ : BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: $50 \text{M}\Omega \mu \text{F}$ or $1000 \text{M}\Omega$ whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ:Within $\pm 12.5\%$ Note 4 $\tan \delta$: BJ: 5.0% max. Note 4. F: 11.0% max. Insulation resistance: $50~\mathrm{M}\Omega~\mathrm{\mu F}$ or $1000~\mathrm{M}\Omega$ whichever is smaller. Note 5	Multilayer: Preconditioning: Thermal treatment (at 150°C for 1 hr) (Applicable to Class 2.) Temperature: 40±2°C Humidity: 90 to 95% RH Duration: 500 ⁺²⁴ hrs Recovery: Recovery for the following period under th standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 ⁺²⁴ hrs Recovery: Recovery for the following period under th standard condition after the removal from test chamber. 6~24 hrs (Class 1)

Multilayer Ceramic Capacitor Chips

		Specifie	ed Value			
Item	Temperature Compensating (Class 1)		High Permitti	vity (Class 2)	Test Methods and Remarks	
	Standard	High Frequency Type	Standard Note1	High Value		
16.Loading under Damp Heat	Appearance: No abnormality Capacitance change: Within ±7.5% or ± 0.75pF, whichever is larger. Q: C≧30 pF: Q≧200 C<30 pF: Q≥100 + 10C/3 C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: C≤2 pF: Within ±0.4 pF C>2 pF: Within ±0.75 pF C: Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: $25~\mathrm{M}\Omega\mu\mathrm{F}$ or $500~\mathrm{M}\Omega$, whichever is the smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 5.0% max. F: 11% max. Note 4 Insulation resistance: $25~\mathrm{M}\Omega\mu\mathrm{F}$ or $500~\mathrm{M}\Omega$, whichever is the smaller. Note 5	According to JIS C 5102 Clause 9. 9. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature: 40 ±2°C Humidity: 90 to 95% RH Duration: 500 +24 hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. (Class 1,2) Recovery: Recovery for the following period under the standa condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 60±2°C Humidity: 90 to 95% RH Duration: 500 +24 hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. Recovery: 6~24 hrs of recovery under the standar condition after the removal from test chamber	
17.Loading at High Temperature	Appearance: No abnormality Capacitance change: Within ±3% or ±0.3pF, whichever is larger. Q: C≧30 pF : Q≧350 10≦C<30 pF: Q≧275 +2.5C C<10 pF: Q≧200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±3% or ± 0.3pF, whichever is larger. Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ F: Within $\pm 30\%$ Note 4 tan δ : BJ: 4.0% max. F: 7.5% max. Note 4 Insulation resistance: $50\mathrm{M}\Omega\mu\mathrm{F}$ or $1000\mathrm{M}\Omega$, whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ: Within $\pm 12.5\%$ Within $\pm 20\% * \%$ Within $\pm 25\% * \%$ F: Within $\pm 30\%$ Note 4 $\tan \delta$: BJ: 5.0% max. F: 11% max. Note 4 Insulation resistance: 50 M Ω μ F or 1000 M Ω , whichever is smaller. Note 5	According to JIS C 5102 clause 9.10. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature:125±3°C (Class 1, Class 2: B, BJ (X7R)) 85±2°C (Class 2: BJ,F) Duration: 1000-48 hrs Applied voltage: Rated voltage ×2 Note 6 Recovery: Recovery for the following period under the standard condition after the removal from test chamber As for Ni product, thermal treatment shall be performed prior to the recovery. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High—Frequency Multilayer: Temperature: 125±3°C (Class 1) Duration: 1000-48 hrs Applied voltage: Rated voltage × 2 Recovery: 6~24 hrs of recovery under the standard condition after the removal from test chamber As for Ni product, thermal treatment shall be performed prior to the recovery.	

Note 1 :For 105 type, specified in "High value".

Note 2 :Thermal treatment (Multilayer): 1 hr of thermal treatment at 150 +0/-10 °C followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement.

Note 3 :Voltage treatment (Multilayer): 1 hr of voltage treatment and voltage for testing followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement.

Note 4, 5 :The figure indicates typical inspection. Please refer to individual specifications.

Note 6 :Some of the parts are applicable in rated voltage × 1.5. Please refer to individual specifications.

Note on standard condition: "standard condition" referred to herein is defined as follows: 5 to 35°C of temperature, 45 to 85% relative humidity, and 86 to 106kPa of air pressure.

When there are questions concerning measurement results: In order to provide correlation data, the test shall be conducted under condition of 20±2°C of temperature, 60 to 70% relative humidity, and 86 to 106kPa of air pressure. Unless otherwise specified, all the tests are conducted under the "standard condition."

Stages	Precautions	Technical considerations
I.Circuit Design	Verification of operating environment, electrical rating and performance 1. A malfunction in medical equipment, spacecraft, nuclear reactors, etc. may cause serious harm to human life or have severe social ramifications. As such, any capacitors to be used in such equipment may require higher safety and/or reliability considerations and should be clearly differentiated from components used in general purpose applications. Operating Voltage (Verification of Rated voltage) 1. The operating voltage for capacitors must always be lower than their rated values. If an AC voltage is loaded on a DC voltage, the sum of the two peak voltages should be lower than the rated value of the capacitor chosen. For a circuit where both an AC and a pulse voltage may be present, the sum of their peak voltages should also be lower than the capacitor's rated voltage. 2. Even if the applied voltage is lower than the rated value, the reliability of capacitors might be reduced if either a high frequency AC voltage or a pulse voltage having rapid rise time	
2.PCB Design	Pattern configurations (Design of Land-patterns) 1. When capacitors are mounted on a PCB, the amount of solder used (size of fillet) can directly affect capacitor performance. Therefore, the following items must be carefully considered in the design of solder land patterns: (1) The amount of solder applied can affect the ability of chips to withstand mechanical stresses which may lead to breaking or cracking. Therefore, when designing land-patterns it is necessary to consider the appropriate size and configuration of the solder pads which in turn determines the amount of solder necessary to form the fillets. (2) When more than one part is jointly soldered onto the same land or pad, the pad must be designed so that each component's soldering point is separated by solder-resist.	1.The following diagrams and tables show some examples of recommended patterns to prevent excessive solder amourts. (larger fillets which extend above the component end terminations) Examples of improper pattern designs are also shown. (1) Recommended land dimensions for a typical chip capacitor land patterns for PCBs Land pattern Chip capacitor Solder-resist Chip capacitor Chip capacitor Chip capacitor Solder-resist Chip capacitor Type 107 212 316 325 Size W 0.8 1.25 1.6 2.5 A 0.8~1.0 1.0~1.4 1.8~2.5 1.8~2.5 B 0.5~0.8 0.8~1.5 0.8~1.7 0.8~1.7 0.8~1.7 C 0.6~0.8 0.9~1.2 1.2~1.6 1.8~2.5
		Type

Stages	Precautions	Technical considerations
		Land pattern Solder-resist
2.PCB Design		(2) Examples of good and bad solder application Items Not recommended Recommended
		Mixed mounting of SMD and leaded components
		Component placement close to the chassis
		Hand-soldering of leaded components near mounted components
		Horizontal component placement
	Pattern configurations (Capacitor layout on panelized [breakaway] PC boards) 1. After capacitors have been mounted on the boards, chips	1-1. The following are examples of good and bad capacitor layout; SMD capacitors should be located to minimize any possible mechanical stresses from board warp or deflection.
	can be subjected to mechanical stresses in subsequent	Not recommended Recommended
	manufacturing processes (PCB cutting, board inspection, mounting of additional parts, assembly into the chassis, wave soldering the reflow soldered boards etc.) For this reason, planning pattern configurations and the position of SMD capacitors should be carefully performed to minimize stress.	Deflection of the board Deflection of the board Deflection of the board Deflection of the mechanical stresses that are anticipated.
		1-2. To layout the capacitors for the breakaway PC board, it should be noted that the amount of mechanical stresses given will vary depending on capacitor layout. The example below shows recommendations for better design.
		Perforation C D Slit B B Slit Magnitude of stress A>B = C>D>E
		1-3. When breaking PC boards along their perforations, the amount of mechanical stress on the capacitors can vary according to the method used. The following methods are listed in order from least stressful to most stressful: push-back, slit, V-grooving, and perforation. Thus, any ideal SMD capacitor layout must also consider the PCB splitting procedure.

Stages	Precautions	Technical considerations
3.Considerations for automatic placement	Adjustment of mounting machine 1. Excessive impact load should not be imposed on the capacitors when mounting onto the PC boards. 2. The maintenance and inspection of the mounters should be conducted periodically.	1. If the lower limit of the pick-up nozzle is low, too much force may be imposed on t capacitors, causing damage. To avoid this, the following points should be consider before lowering the pick-up nozzle: (1) The lower limit of the pick-up nozzle should be adjusted to the surface level of t PC board after correcting for deflection of the board. (2) The pick-up pressure should be adjusted between 1 and 3 N static loads. (3) To reduce the amount of deflection of the board caused by impact of the pick-nozzle, supporting pins or back-up pins should be used under the PC board. The following diagrams show some typical examples of good pick-up nozzle placement:
		Not recommended Recommended
		Single-sided mounting Supporting pin
		Double-sided mounting Solder peeling Cracks Supporting pin
		2. As the alignment pin wears out, adjustment of the nozzle height can cause chipping cracking of the capacitors because of mechanical impact on the capacitors. To avoid this, the monitoring of the width between the alignment pin in the stopped position, a maintenance, inspection and replacement of the pin should be conducted periodically.
	Selection of Adhesives 1. Mounting capacitors with adhesives in preliminary assembly, before the soldering stage, may lead to degraded capacitor characteristics unless the following factors are appropriately checked; the size of land patterns, type of adhesive, amount applied, hardening temperature and hardening period. Therefore, it is imperative to consult the manufacturer of the adhesives on proper usage and amounts of adhesive to use.	 maintenance, inspection and replacement of the pin should be conducted periodically. 1. Some adhesives may cause reduced insulation resistance. The difference betwee the shrinkage percentage of the adhesive and that of the capacitors may result stresses on the capacitors and lead to cracking. Moreover, too little or too musual adhesive applied to the board may adversely affect component placement, so the following precautions should be noted in the application of adhesives. (1) Required adhesive characteristics a. The adhesive should be strong enough to hold parts on the board during the mounting & solder process. b. The adhesive should have sufficient strength at high temperatures. c. The adhesive should have good coating and thickness consistency. d. The adhesive should be used during its prescribed shelf life. e. The adhesive should harden rapidly f. The adhesive must not be contaminated. g. The adhesive should have excellent insulation characteristics. h. The adhesive should not be toxic and have no emission of toxic gasses. (2) The recommended amount of adhesives is as follows; Figure 212/316 case sizes as examples a 0.3mm min b 100 ~120 μm c Adhesives should not contact the pad Amount of adhesive After capacitors are bonded After capacitors are bonded
		b c c

Stages	Precautions	Technical considerations
4. Soldering	Selection of Flux 1. Since flux may have a significant effect on the performance of capacitors, it is necessary to verify the following conditions prior to use; (1) Flux used should be with less than or equal to 0.1 wt% (equivelent to chroline) of halogenated content. Flux having a strong acidity content should not be applied. (2) When soldering capacitors on the board, the amount of flux applied should be controlled at the optimum level. (3) When using water-soluble flux, special care should be taken to properly clean the boards.	 1-1. When too much halogenated substance (Chlorine, etc.) content is used to activate the flux, or highly acidic flux is used, an excessive amount of residue after soldering may lead to corrosion of the terminal electrodes or degradation of insulation resistance on the surface of the capacitors. 1-2. Flux is used to increase solderability in flow soldering, but if too much is applied, a large amount of flux gas may be emitted and may detrimentally affect solderability. To minimize the amount of flux applied, it is recommended to use a flux-bubbling system. 1-3. Since the residue of water-soluble flux is easily dissolved by water content in the air, the residue on the surface of capacitors in high humidity conditions may cause a degradation of insulation resistance and therefore affect the reliability of the components. The cleaning methods and the capability of the machines used should also be considered carefully when selecting water-soluble flux.
	Soldering Temperature, time, amount of solder, etc. are specified in accordance with the following recommended conditions.	1-1. Preheating when soldering Heating: Ceramic chip components should be preheated to within 100 to 130°C of the soldering. Cooling: The temperature difference between the components and cleaning process should not be greater than 100°C. Ceramic chip capacitors are susceptible to thermal shock when exposed to rapid or concentrated heating or rapid cooling. Therefore, the soldering process must be conducted with great care so as to prevent malfunction of the components due to excessive thermal shock.
	Sn-Zn solder paste can affect MLCC reliability performance. Please contact us prior to usage.	Recommended conditions for soldering [Reflow soldering] Temperature profile Temperature Out of the soldering of the solde
		2. Because excessive dwell times can detrimentally affect solderability, soldering duration should be kept as close to recommended times as possible. [Wave soldering] Temperature profile Temperature (*C) 300 Peak 260°C max 10 sec max 10 sec max Preheating 300 Preheating 40 cooling 150°C 10 sec min **Ceramic chip components should be preheated within 100 to 130°C of the soldering. **Except for reflow soldering type. Caution 1. Make sure the capacitors are preheated sufficiently. 2. The temperature difference between the capacitor and melted solder should not be greater than 100 to 130°C 3. Cooling after soldering should be as gradual as possible. 4. Wave soldering must not be applied to the capacitors designated as for reflow soldering soldering should be as gradual as possible.

Stages	Precautions	Technical considerations
4. Soldering		[Hand soldering] Temperature profile Temperature (*C) (Pb free soldering) 400 Preheating 300 Over 1 minute Within 3 seconds **The soldering iron should not directly touch the capacitor. **The soldering iron should not directly touch the capacitor. Temperature (*C) (Pb free soldering) **Add signal (*C) (*Add
5.Cleaning	Cleaning conditions 1. When cleaning the PC board after the capacitors are all mounted, select the appropriate cleaning solution according to the type of flux used and purpose of the cleaning (e.g. to remove soldering flux or other materials from the production process.) 2. Cleaning conditions should be determined after verifying, through a test run, that the cleaning process does not affect the capacitor's characteristics.	1. The use of inappropriate solutions can cause foreign substances such as flux residue to adhere to the capacitor or deteriorate the capacitor's outer coating, resulting in a degradation of the capacitor's electrical properties (especially insulation resistance). 2. Inappropriate cleaning conditions (insufficient or excessive cleaning) may detrimentally affect the performance of the capacitors. (1) Excessive cleaning In the case of ultrasonic cleaning, too much power output can cause excessive vibration of the PC board which may lead to the cracking of the capacitor or the soldered portion, or decrease the terminal electrodes' strength. Thus the following conditions should be carefully checked; Ultrasonic output Below 20 W/ & Ultrasonic frequency Below 40 kHz Ultrasonic washing period 5 min. or less
6.Post cleaning processes	1. With some type of resins a decomposition gas or chemical reaction vapor may remain inside the resin during the hardening period or while left under normal storage conditions resulting in the deterioration of the capacitor's performance. 2. When a resin's hardening temperature is higher than the capacitor's operating temperature, the stresses generated by the excess heat may lead to capacitor damage or destruction. The use of such resins, molding materials etc. is not recommended.	
7.Handling	Breakaway PC boards (splitting along perforations) 1. When splitting the PC board after mounting capacitors and other components, care is required so as not to give any stresses of deflection or twisting to the board. 2. Board separation should not be done manually, but by using the appropriate devices. Mechanical considerations 1. Be careful not to subject the capacitors to excessive mechanical shocks. (1) If ceramic capacitors are dropped onto the floor or a hard surface, they should not be used. (2) When handling the mounted boards, be careful that the mounted components do not come in contact with or bump against other boards or components.	

Stages	Precautions	Technical considerations
8.Storage conditions	Storage 1. To maintain the solderability of terminal electrodes and to keep the packaging material in good condition, care must be taken to control temperature and humidity in the storage area. Humidity should especially be kept as low as possible. Recommended conditions Ambient temperature Below 30°C Humidity Below 70% RH The ambient temperature must be kept below 40°C. Even under ideal storage conditions capacitor electrode solderability decreases as time passes, so should be used within 6 months from the time of delivery. Ceramic chip capacitors should be kept where no chlorine or sulfur exists in the air. 2. The capacitance value of high dielectric constant capacitors (type 2 &3) will gradually decrease with the passage of time, so this should be taken into consideration in the circuit design. If such a capacitance reduction occurs, a heat treatment of 150°C for 1hour will return the capacitance to its initial level.	If the parts are stored in a high temperature and humidity environment, problems such as reduced solderability caused by oxidation of terminal electrodes and deterioration of taping/packaging materials may take place. For this reason, components should be used within 6 months from the time of delivery. If exceeding the above period, please check solderability before using the capacitors.